

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2668	716/4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:03
L2	2050	716/5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:03
L3	1634	716/6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:03
L4	0	(716/4).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:12
L5	0	(716/4).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:12
L6	0	(716/5).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:12
L7	0	(716/6).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:13
L8	0	("716"/\$).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:13
L9	1	(partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:15

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L10	1	(702/181).ccls. and (partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:25
L11	0	((partition\$4 same (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:26
L12	0	((partition\$4 and (logic adj block\$2)) and ((multi\$3 adj cycle\$2) adj (setup adj sequence\$2)) and (constraint adj set\$4)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:26
L13	1	((partition\$4 and (logic adj block\$2)) and ((multi\$3 adj cycle\$2) and (setup adj sequence\$2)) and (constraint adj set\$4)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:27
L14	1	(encod\$4) and ((scan adj cell) adj replac\$6) and (cost adj function) and (affinity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:31
L15	1	((encod\$4) and ((scan adj cell) adj replac\$6) and (cost adj function) and (affinity)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:31
L16	1	(select\$6) and (characterization) and ((scan adj cell\$2) adj replac\$6) and (cost adj function) and (affinity)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:33
L17	1	((select\$6) and (characterization) and ((scan adj cell\$2) adj replac\$6) and (cost adj function) and (affinity)).CLM.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/05/30 15:33

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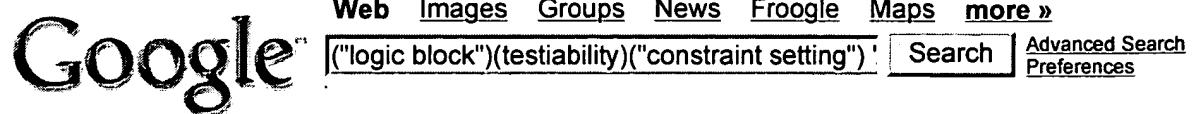
Your search matched **0** documents.A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.» [Search Options](#)[View Session History](#)[Modify Search](#)[New Search](#) Check to search only within this results setDisplay Format: Citation Citation & Abstract» [Key](#)**IEEE JNL** IEEE Journal or Magazine**IEE JNL** IEE Journal or Magazine**IEEE CNF** IEEE Conference Proceeding**IEE CNF** IEE Conference Proceeding**IEEE STD** IEEE Standard**No results were found.**

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Method and system for providing fast design for testability wherein the steps of determining the **cost function** and establishing the **affinity** ... one or more **scan cells** having the closest target characteristics[www.freshpatents.com/ Method-and-system-for-providing-fast-design-for-testability-prototyping-in-integrate...](http://www.freshpatents.com/Method-and-system-for-providing-fast-design-for-testability-prototyping-in-integrate...) - 21k - Supplemental Result - [Cached](#) - [Similar pages](#)**DATE 2003 Abstracts****A Partition-Based Approach for Identifying Failing Scan Cells in Scan-BIST with ... cost function**-driven high-level synthesis, such that on-line testing ...www.sigda.org/Archives/ProceedingArchives/Date/papers/2003/date03/htmfiles/sun_sgi/frames/dateabs.htm - 238k -[Cached](#) - [Similar pages](#)*In order to show you the most relevant results, we have omitted some entries very similar to the 2 already displayed.**If you like, you can [repeat the search with the omitted results included](#).*Try your search again on [Google Book Search](#)Free! Speed up the web. [Download the Google Web Accelerator](#). [Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

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